



PCN# 20140306001
Design Revision (NBTI Fix for Select TPS40077PWP Devices)
Change Notification / Sample Request

Date: 3/13/2014
To: MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN_ww_admin_team@list.ti.com).

Sincerely,

PCN Team
SC Business Services
Phone: +1(214) 480-6037
Fax: +1(214) 480-6659

20140306001
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
TPS40077PWP	null
TPS40077PWPR	null
TPS40077PWPG4	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20140306001			PCN Date:	03/13/2014
Title:	Design Revision (NBTI Fix for Select TPS40077PWP Devices)				
Customer Contact:	PCN Manager	Phone:	+1(214)480-6037	Dept:	Quality Services
Proposed 1st Ship Date:	06/13/2014	Estimated Sample Availability:			Date provided at sample request
Change Type:					
<input type="checkbox"/> Assembly Site	<input type="checkbox"/> Assembly Process	<input type="checkbox"/> Assembly Materials			
<input checked="" type="checkbox"/> Design	<input type="checkbox"/> Electrical Specification	<input type="checkbox"/> Mechanical Specification			
<input type="checkbox"/> Test Site	<input type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Process			
<input type="checkbox"/> Wafer Bump Site	<input type="checkbox"/> Wafer Bump Material	<input type="checkbox"/> Wafer Bump Process			
<input type="checkbox"/> Wafer Fab Site	<input type="checkbox"/> Wafer Fab Materials	<input type="checkbox"/> Wafer Fab Process			
	<input type="checkbox"/> Part number change				
PCN Details					
Description of Change:					
This notification is to inform of a design revision for select TPS40077PWP devices. This design change does not affect the device's guaranteed datasheet specifications or electrical performance. The affected devices are listed in the "Product Affected" section.					
The table below describes changes that were made:					
Description of Change		Benefit of Change			
Continuous improvement to remove sensitivity over time to negative bias temperature instability (NBTI) under high temperature conditions.		Improve reliability			
Reason for Change:					
Improve reliability					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):					
None					
Changes to product identification resulting from this PCN:					
None					
Product Affected:					
TPS40077PWP	TPS40077PWPG4	TPS40077PWPR	TPS40077PWPRG4		

Qualification Data: Approved 2/27/2014

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qual Vehicle 1: TPS40077PWP

Package/Die Construction Details

Assembly Site:	TAI	# Pins-Designator, Family:	16-PWP, HTSSOP
Fab Process:	LBC4	Die Revision:	C
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test		Conditions	Sample Size (PASS/FAIL)
High Temp Operating Life		125C (168, 500, 1000 Hrs)	80/0
Electrical Characterization, side by side		–	Pass
ESD CDM		+/- 250V	3/0
ESD HBM		+/- 1000V	3/0
Latch-up		(per JESD78)	6/0

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or to your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com